

RELIABILITY DATA

LTC5505/07/08/09/30/31/32/33

8/21/2006

• OPERATING LIFE TEST

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS ⁽¹⁾ AT +125°C	NUMBER OF ⁽²⁾ FAILURES
SOIC/SOT/MSOP	155	0201	0213	155.00	0
SSOP/TSSOP	386	0302	0421	282.94	0
	541			437.94	0

• PRESSURE COOKER TEST AT 15 PSIG, +121°C

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS	NUMBER OF FAILURES
SOIC/SOT/MSOP	2,296	0133	2335	351.01	0
QFN/DFN	227	0345	0525	30.22	0
	2,523			381.24	0

• TEMP CYCLE FROM -65°C to +150°C

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
SOIC/SOT/MSOP	1,978	0133	0608	613.00	0
QFN/DFN	227	0429	0525	92.00	0
	2,205			705.00	0

• THERMAL SHOCK FROM -65°C to +150°C

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
SOIC/SOT/MSOP	1,991	0204	0608	698.10	0
QFN/DFN	225	0345	0525	90.90	0
	2,216			789.00	0

(1) Assumes Activation Energy = 0.7 Electron Volts

(2) Failure Rate Equivalent to +55°C, 60% Confidence Level = 27.03 FITS

(3) Mean Time Between Failures in Years = 4,220

Note: 1 FIT = 1 Failure in One Billion Hours.